

FEI XL40 SEM



Main System Features:

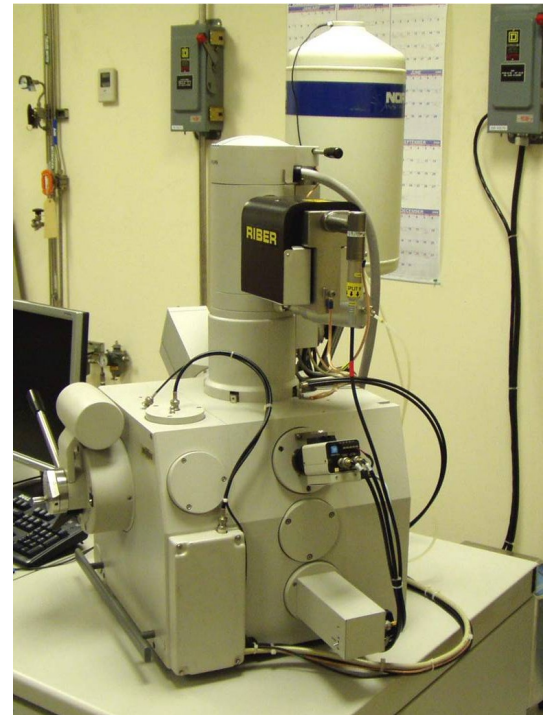
- Originally installed 1996 (Dupont, Richmond, VA)
- Serial Number D717
- LaB₆ source with 6-position bias control
- Windows NT
- MCtrl version 6.0
- Fully integrated image storage
- ET type Secondary Electron Detector
- FEI (Philips) Solid State BSD detector
- CCD Chamberscope
- 35 degree X-Ray takeoff angle
- Sample holders, supplies, tools, as available

Original Performance Specs:

- 3nm at 30kV; 15nm at 1kV
- Magnification range: 10x to 400,000x
- Accelerating Voltage: 0.2 to 30kV

Stage & Specimen Handling:

- Drawer type door
- 5 axis stage (XYZRT) - XYR motorized
- 150mm motorized travel in X and Y
- Manual Tilt and Z
- External Z adjust of 37mm
- Maximum free space of 55mm for thick specimens
- Interior chamber size 379mm x 325mm x 315mm
- Total of 8 ports available including BNC electrical feedthru



Facilities:

- Oil Diffusion Pump (ODP) main vacuum
- One Backing (roughing) pump
- Water Cooled Chiller for ODP

Note:

- EDX System shown is *not included*
EDX can be quoted optionally

For more information, please contact:

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